# International

- Advanced Process Technology
- Dynamic dv/dt Rating
- 175°C Operating Temperature
- Fast Switching
- Fully Avalanche Rated
- Lead-Free

#### Description

Fifth Generation HEXFETs from International Rectifier utilize advanced processing techniques to achieve extremely low on-resistance per silicon area. This benefit, combined with the fast switching speed and ruggedized device design that HEXFET Power MOSFETs are well known for, provides the designer with an extremely efficient and reliable device for use in a wide variety of applications.

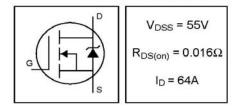
The TO-247 package is preferred for commercialindustrial applications where higher power levels preclude the use of TO-220 devices. The TO-247 is similar but superior to the earlier TO-218 package because of its isolated mounting hole.

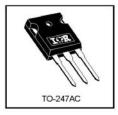
### Absolute Maximum Ratings

PD-95422

# IRFP048NPbF

#### HEXFET<sup>®</sup> Power MOSFET





	Parameter	Max.	Units	
I <sub>D</sub> @ T <sub>C</sub> = 25°C	Continuous Drain Current, V <sub>GS</sub> @ 10V	64		
I <sub>D</sub> @ T <sub>C</sub> = 100°C	Continuous Drain Current, V <sub>GS</sub> @ 10V	45	A	
I <sub>DM</sub>	Pulsed Drain Current 00	210		
$P_{D}@T_{C} = 25^{\circ}C$	Power Dissipation	140	W	
	Linear Derating Factor	0.90	W/°C	
V <sub>GS</sub>	Gate-to-Source Voltage	± 20	V	
E <sub>AS</sub>	Single Pulse Avalanche Energy 23	270	mJ	
AR	Avalanche Current <sup>®</sup>	32	A	
E <sub>AR</sub>	Repetitive Avalanche Energy①	14	mJ	
d∨/dt	Peak Diode Recovery dv/dt 35	5.0	V/ns	
TJ	Operating Junction and	-55 to + 175		
T <sub>STG</sub>	Storage Temperature Range		°C	
	Soldering Temperature, for 10 seconds	300 (1.6mm from case )		
	Mounting torque, 6-32 or M3 srew	10 lbf•in (1.1N•m)		

### **Thermal Resistance**

	Parameter	Тур.	Max.	Units
R <sub>eJC</sub>	Junction-to-Case		1.1	
R <sub>0CS</sub>	Case-to-Sink, Flat, Greased Surface	0.24		°CW
R <sub>BJA</sub>	Junction-to-Ambient		40	

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# International **IOR** Rectifier

### Electrical Characteristics @ $T_J = 25^{\circ}C$ (unless otherwise specified)

	Parameter	Min.	Тур.	Max.	Units	Conditions
V <sub>(BR)DSS</sub>	Drain-to-Source Breakdown Voltage	55			V	$V_{GS} = 0V, I_D = 250 \mu A$
ΔV(BR)DSS/ΔTJ	Breakdown Voltage Temp. Coefficient		0.052	-	V/°C	Reference to 25°C, I <sub>D</sub> = 1mA <sup>®</sup>
R <sub>DS(on)</sub>	Static Drain-to-Source On-Resistance	—		0.016	Ω	V <sub>GS</sub> = 10V, I <sub>D</sub> = 37A ④
V <sub>GS(th)</sub>	Gate Threshold Voltage	2.0		4.0	V	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$
<b>g</b> fs	Forward Transconductance	22			S	$V_{DS} = 25V, I_{D} = 32A$ (s)
1	Drain-to-Source Leakage Current		<u>1777 - 19</u>	25		V <sub>DS</sub> = 55V, V <sub>GS</sub> = 0V
IDSS	Drail-to-Source Leakage Current		<u></u>	250	μA	$V_{DS} = 44V, V_{GS} = 0V, T_{J} = 150^{\circ}C$
	Gate-to-Source Forward Leakage		<u></u>	100	n۸	V <sub>GS</sub> = 20V
IGSS	Gate-to-Source Reverse Leakage	<u> </u>	<u></u>	-100	nA	V <sub>GS</sub> = -20V
Qg	Total Gate Charge			89		I <sub>D</sub> = 32A
Q <sub>gs</sub>	Gate-to-Source Charge			20	nC	V <sub>DS</sub> = 44V
Q <sub>gd</sub>	Gate-to-Drain ("Miller") Charge		<u></u>	39		V <sub>GS</sub> = 10V, See Fig. 6 and 13 @ ⑤
t <sub>d(on)</sub>	Turn-On Delay Time		11			V <sub>DD</sub> = 28V
tr	Rise Time		78			I <sub>D</sub> = 32A
t <sub>d(off)</sub>	Turn-Off Delay Time		32		ns	R <sub>G</sub> = 5.1Ω
t <sub>f</sub>	Fall Time		48			R <sub>D</sub> = 0.85Ω, See Fig. 10 ④⑤
r	Internal Decision in the test sector		5.0			Between lead,
L <sub>D</sub>	Internal Drain Inductance		5.0		- 211	6mm (0.25in.)
L <sub>S</sub>	Internal Source Inductance		13		nH	from package
						and center of die contact
Ciss	Input Capacitance		1900			V <sub>GS</sub> = 0V
Coss	Output Capacitance		620		pF	V <sub>DS</sub> = 25V
C <sub>rss</sub>	Reverse Transfer Capacitance		270			f = 1.0MHz, See Fig. 5⑤

### Source-Drain Ratings and Characteristics

	Parameter	Min.	Тур.	Мах.	Units	Conditions
Is	Continuous Source Current			45		MOSFET symbol
	(Body Diode)			40		showing the
I <sub>SM</sub>	Pulsed Source Current		21	210	- A	integral reverse • 🗸 🕰
	(Body Diode) 🛈 🕲					p-n junction diode.
VSD	Diode Forward Voltage		ļ	1.3	V	$T_{J} = 25^{\circ}C$ , $I_{S} = 37A$ , $V_{GS} = 0V$ (4)
trr	Reverse Recovery Time		94	140	ns	T <sub>J</sub> = 25°C, I <sub>F</sub> = 32A
Qrr	Reverse RecoveryCharge	<u> </u>	360	540	nC	di/dt = 100A/µs ⊕⑤

#### Notes:

- $\ensuremath{\mathbb O}$  Repetitive rating; pulse width limited by max. junction temperature. ( See fig. 11 )
- 2  $V_{DD}$  = 25V, starting  $T_{\rm J}$  = 25°C, L = 530 $\mu H$   $R_{\rm G}$  = 25 $\Omega,$   $I_{\rm AS}$  = 32A. (See Figure 12)
- $\textcircled{\mbox{0.5}}$  Pulse width  $\leq$  300 $\mu s;$  duty cycle  $\leq$  2%.

S Uses IRFZ48N data and test conditions

3 I\_{SD}  $\leq$  32A, di/dt  $\leq$  250A/µs, V\_{DD}  $\leq$  V\_{(BR)DSS}, T\_{\rm J} \leq 175°C

# International **TOR** Rectifier

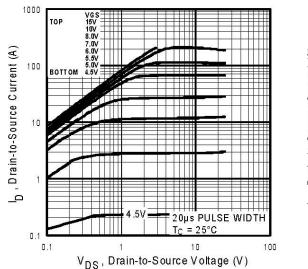


Fig 1. Typical Output Characteristics

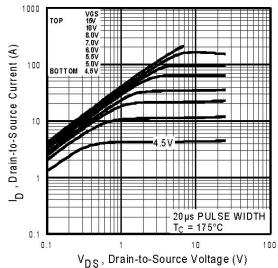


Fig 2. Typical Output Characteristics

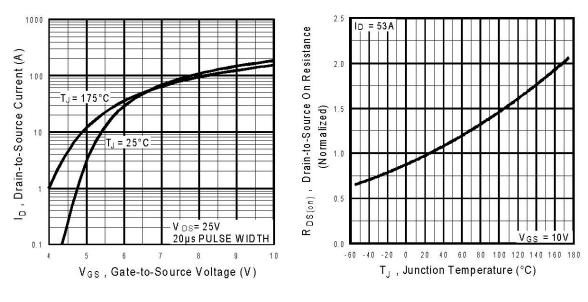
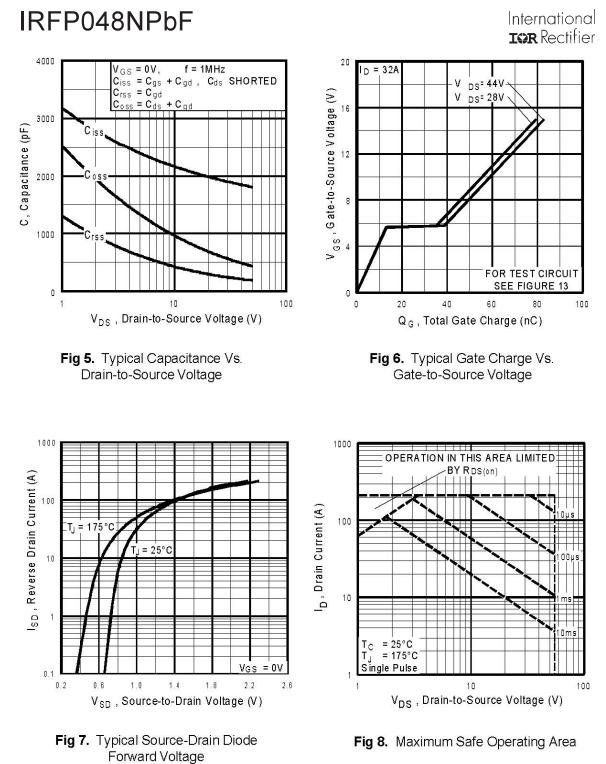


Fig 3. Typical Transfer Characteristics

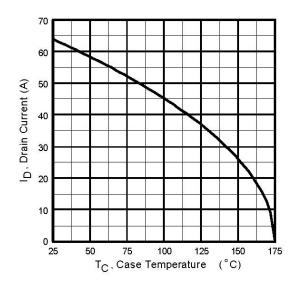
Fig 4. Normalized On-Resistance Vs. Temperature

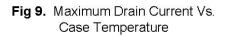




# International

## IRFP048NPbF





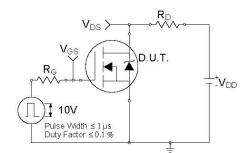


Fig 10a. Switching Time Test Circuit

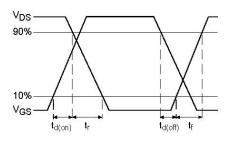


Fig 10b. Switching Time Waveforms

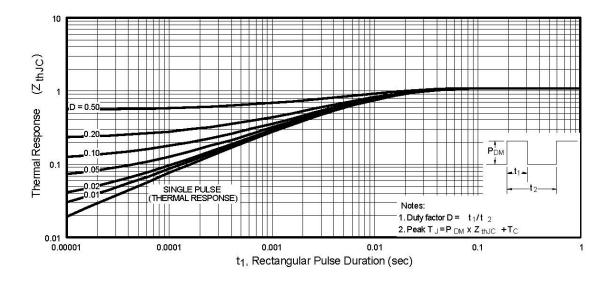


Fig 11. Maximum Effective Transient Thermal Impedance, Junction-to-Case

# International

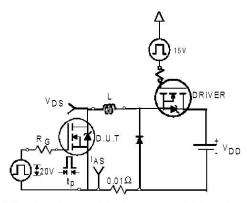


Fig 12a. Unclamped Inductive Test Circuit

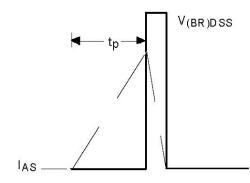


Fig 12b. Unclamped Inductive Waveforms

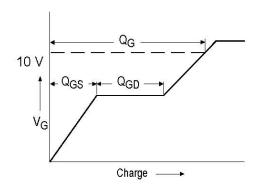


Fig 13a. Basic Gate Charge Waveform

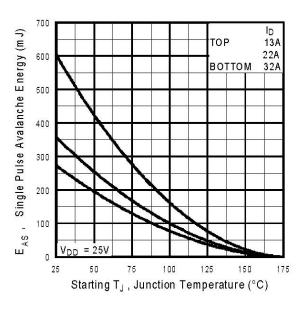


Fig 12c. Maximum Avalanche Energy Vs. Drain Current

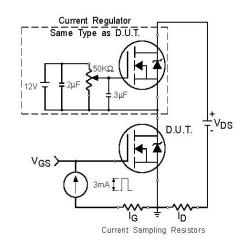
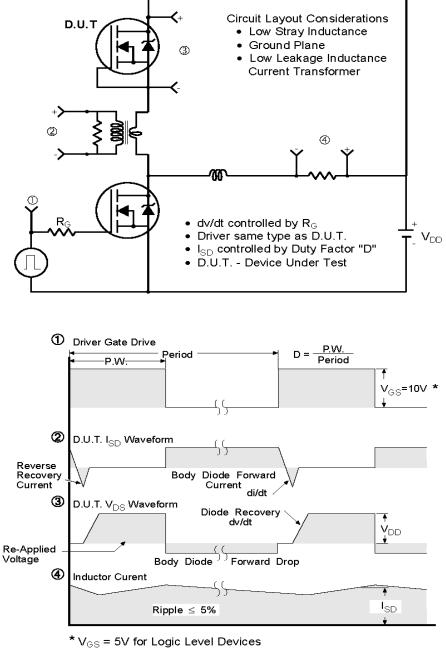


Fig 13b. Gate Charge Test Circuit

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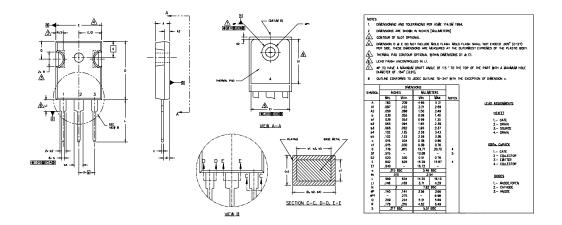
### Peak Diode Recovery dv/dt Test Circuit



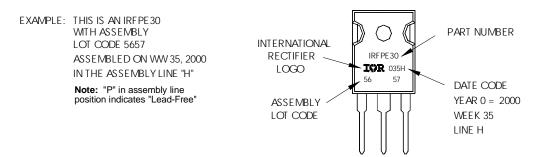


### TO-247AC Package Outline

Dimensions are shown in millimeters (inches)



### **TO-247AC Part Marking Information**



Data and specifications subject to change without notice.

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Note: For the most current drawings please refer to the IR website at: <u>http://www.irf.com/package/</u>

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